

Search Notes

Application/Control No.

10/660,517

Examiner

Alan S. Chen

Applicant(s)/Patent under
Reexamination

CHANG, SHU-MEI

Art Unit

2182

SEARCHED

Class	Subclass	Date	Examiner
710	12	4/28/2005	ASC
	18		
	19		
	63		
	64		
72		↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT	4/28/2005	ASC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner